

Ofertas tecnológicas del eje temático de Fronteras de la Física y Seguridad Civil

- **New low cost lock-in thermographic-based technique for quantitative monitoring of electronic wireless systems**

Technique for functional analysis and quantitative power consumption monitoring in wirelessly powered and pad-free electronic systems. Offer for Industrial License Agreement

Contact

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- **Solution for real power measurement in any high frequency integrated circuit**

Method that faces the challenge to measure the output real power delivered by a system or electronic device to another one in high frequency applications (RF-radio frequency, microwave, millimeter wave). Offer for Industrial License Agreement

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- **Low-cost and non-intrusive real power flux determination for any microelectronic device or system**

Non-invasive method to quantitatively determine the real power flux characteristics. Offer for patent licence or service agreement.

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- **A non-intrusive and low-cost approach to extract figures of merit in any part of high-frequency electronic device**

Non-intrusive, local and low-cost method to extract figures of merit in high-frequency operating-devices.
Offer for licence or service agreement.

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- **Infrared image processing strategies for die-level power devices inspection**

Method to monitoring the temperature evolution at the surface of a power device (under working conditions) to determine the affected regions and apply solutions.
Offer for Licensing and/or co-development.

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